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Application/Control No.	Applicant(s)/Patent under Reexamination
10/712,923	IWASA ET AL.
Examiner	Art Unit
Toan Ton	2871

	SEAR	CHED	
Class	Subclass	Date	Examiner
349	137	7/29/2005	TTON
	44,38		
	110		
	113		
	1,180		
313	503		
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Class	Subclass	Date	Examiner
349	44,110,38	7/29/2005	TTON
	113,137		
313	503		

SEARCH I (INCLUDING SEAR		")
	DATE	EXMR
EAST liquid crystal reflect\$ antireflect\$/anti reflect\$ black mask/matrix light shield\$/block\$ silicon metal\$5 gap\$	7/29/2005	TTON
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